

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Isamu Kobori et al.                      Art Unit : 2812  
Serial No. : 10/623,581                              Examiner : Stanetta Isaac  
Filed : July 22, 2003                              Conf. No. : 6534  
Title : METHOD OF MANUFACTURING A SEMICONDUCTOR METHOD OF  
MANUFACTURING A THIN-FILM TRANSISTOR AND THIN-FILM  
TRANSISTOR

**MAIL STOP RCE**

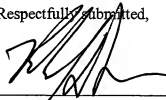
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,



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Date: 7/3/07

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|   |  |                                       |                               |
|---|--|---------------------------------------|-------------------------------|
| Substitute Form PTO-1449<br>(Modified)  | U.S. Department of Commerce<br>Patent and Trademark Office | Attorney's Docket No.<br>07977-024003 | Application No.<br>10/623,581 |
| <b>Information Disclosure Statement<br/>by Applicant</b><br>(Use several sheets if necessary) |  | Applicant<br>Isamu Kobori et al.      |                               |
|   |  | Filing Date<br>July 22, 2003          | Group Art Unit<br>2812        |

(37 CFR §1.98(b))

**U.S. Patent Documents**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
|------------------|-----------|-----------------|------------------|----------|-------|----------|----------------------------|
|                  | AA        |                 |                  |          |       |          |                            |
|                  | AB        |                 |                  |          |       |          |                            |
|                  | AC        |                 |                  |          |       |          |                            |
|                  | AD        |                 |                  |          |       |          |                            |
|                  | AE        |                 |                  |          |       |          |                            |
|                  | AF        |                 |                  |          |       |          |                            |
|                  | AG        |                 |                  |          |       |          |                            |
|                  | AH        |                 |                  |          |       |          |                            |
|                  | AI        |                 |                  |          |       |          |                            |
|                  | AJ        |                 |                  |          |       |          |                            |
|                  | AK        |                 |                  |          |       |          |                            |

**Foreign Patent Documents or Published Foreign Patent Applications**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation |    |
|------------------|-----------|-----------------|------------------|--------------------------|-------|----------|-------------|----|
|                  |           |                 |                  |                          |       |          | Yes         | No |
|                  | AL        | 6-123896        | 05/06/1994       | Japan                    |       |          | Full        |    |
|                  | AM        |                 |                  |                          |       |          |             |    |
|                  | AN        |                 |                  |                          |       |          |             |    |
|                  | AO        |                 |                  |                          |       |          |             |    |
|                  | AP        |                 |                  |                          |       |          |             |    |

**Other Documents (include Author, Title, Date, and Place of Publication)**

| Examiner Initial | Desig. ID | Document |
|------------------|-----------|----------|
|                  | AQ        |          |
|                  | AR        |          |
|                  | AS        |          |
|                  | AT        |          |

|                    |                 |
|--------------------|-----------------|
| Examiner Signature | Date Considered |
|--------------------|-----------------|

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.